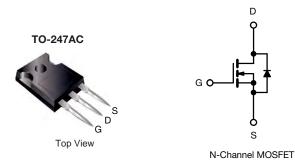


IXFX90N20Q-VB Datasheet

N-Channel 650 V (D-S) Super Junction MOSFET

PRODUCT SUMMARY					
V _{DS} (V) at T _J max.	650				
R _{DS(on)} (Ω) at 25 °C	$V_{GS} = 10 V$	0.19			
Q _g max. (nC)	106				
Q _{gs} (nC)	14				
Q _{gd} (nC)	33				
Configuration	Single				



FEATURES

- Reduced t_{rr}, Q_{rr}, and I_{RRM}
- Low figure-of-merit (FOM) Ron x Qg
- Low input capacitance (Ciss)
- Low switching losses due to reduced Q_{rr}
- Ultra low gate charge (Q_q)

Avalanche energy rated (UIS)

APPLICATIONS

- Telecommunications
 - Server and telecom power supplies
- Lighting
 - High-intensity discharge (HID)
- Fluorescent ballast lighting
- Consumer and computing - ATX power supplies
- Industrial
 - Welding
 - Battery chargers
- Renewable energy
- Solar (PV inverters)
- Switch mode power supplies (SMPS)

= 25 °C, unl	less otherwis	se noted)			
PARAMETER			LIMIT	UNIT	
Drain-Source Voltage			650	V	
Gate-Source Voltage			± 30	v	
V at 10 V	T _C = 25 °C		20		
V _{GS} at 10 V	T _C = 100 °C	۱D	13	А	
Pulsed Drain Current ^a			53		
Linear Derating Factor			1.7	W/°C	
Single Pulse Avalanche Energy ^b			367	mJ	
Maximum Power Dissipation			208	W	
Operating Junction and Storage Temperature Range			-55 to +150	°C	
T _J = 125 °C		d\//d+	37	V/ns	
Reverse Diode dV/dt ^d		uv/dl	31	v/ns	
for	10 s		300	°C	
	V _{GS} at 10 V e T _J = 1	$V_{GS} \text{ at } 10 \text{ V} \qquad \frac{T_C = 25 \text{ °C}}{T_C = 100 \text{ °C}}$	I_{DM} E_{AS} P_{D} $e T_{J}, T_{stg}$ $T_{J} = 125 \ ^{\circ}C dV/dt$	$\begin{tabular}{ c c c c c c } \hline SYMBOL & LIMIT \\ \hline V_{DS} & 650 \\ \hline V_{GS} & \pm 30 \\ \hline V_{GS} & \pm 30 \\ \hline V_{GS} & \pm 10 \ V & \hline T_C = 25 \ ^{\circ}C & I_D & 20 \\ \hline T_C = 100 \ ^{\circ}C & I_D & 13 \\ \hline & I_DM & 53 \\ \hline & I_{DM} & 53 \\ \hline & $I_{T,T}$ & $I_{T,T}$ \\ \hline & E_{AS} & 367 \\ \hline & P_D & 208 \\ \hline & T_J, T_{stg} & -55 to +150$ \\ \hline & $T_J = 125 \ ^{\circ}C$ & dV/dt & 31 \\ \hline \end{tabular}$	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b. $V_{DD} = 50$ V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω , I_{AS} = 5.1 A.

c. 1.6 mm from case.

d. $I_{SD} \leq I_D$, dl/dt = 100 A/µs, starting T_J = 25 °C.



THERMAL RESISTANCE RATI	NGS							
PARAMETER	SYMBOL	TYP.	TYP. MAX.		UNIT		UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-		62		1		
Maximum Junction-to-Case (Drain)	R _{thJC}	-	- 0.5			°C/W		
SPECIFICATIONS ($T_J = 25 \degree C$, u	Inless otherw	ise noted)						
PARAMETER	SYMBOL		T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT
Static	•	-						<u> </u>
Drain-Source Breakdown Voltage	V _{DS}	V _{GS}	= 0 V, I _D =	250 µA	650	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C,	I _D = 1 mA	-	0.67	-	V/°C
Gate-Source Threshold Voltage (N)	V _{GS(th)}		= V _{GS} , I _D =		2	-	4	V
		$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA	
Gate-Source Leakage	-Source Leakage I _{GSS} V _{GS} = ± 30 V) V	-	-	± 1	μA	
Zero Gate Voltage Drain Current			$V_{DS} = 520 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$		-	-	1	
	IDSS		$V_{DS} = 520 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 125 \text{ °C}$			-	500	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V		_D = 11 A	-	0.19	-	Ω
Forward Transconductance	9fs		= 30 V, I _D	= 11 A	-	7.0	-	S
Dynamic	I	-+			ļ	<u>.</u>	ļ	<u>.</u>
Input Capacitance	C _{iss}		V _{GS} = 0 V, V _{DS} = 100 V,		-	2322	-	-
Output Capacitance	C _{oss}	_			-	105	-	
Reverse Transfer Capacitance	C _{rss}	f = 1 MHz V _{DS} = 0 V to 520 V, V _{GS} = 0 V		-	4	-	pF	
Effective Output Capacitance, Energy Related ^a	C _{o(er)}			-	84	-		
Effective Output Capacitance, Time Related ^b	C _{o(tr)}			-	293	-		
Total Gate Charge	Qg				-	71	106	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V I _D = 11 A, V _{DS} = 520 V		-	14	-	nC	
Gate-Drain Charge	Q _{gd}				-	33	-	1
Turn-On Delay Time	t _{d(on)}		V_{DD} = 520 V, I _D = 11 A, V _{GS} = 10 V, R _g = 9.1 Ω		-	22	44	- ns
Rise Time	t _r	- V_D =			-	34	68	
Turn-Off Delay Time	t _{d(off)}	V _{GS} :			-	68	102	
Fall Time	t _f			-	42	84	1	
Gate Input Resistance	R _g	f = 1 MHz, open drain		-	0.78	-	Ω	
Drain-Source Body Diode Characteristi								
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	21	- A	
Pulsed Diode Forward Current	I _{SM}			-	-	53		
Diode Forward Voltage	V _{SD}	T _J = 25 °C, I _S = 11 A, V _{GS} = 0 V		-	0.9	1.2	V	
Reverse Recovery Time	t _{rr}	$T_{J} = 25 \text{ °C}, I_{F} = I_{S} = 11 \text{ A},$ $dI/dt = 100 \text{ A}/\mu\text{s}, V_{R} = 25 \text{ V}$		-	160	-	ns	
Reverse Recovery Charge	Q _{rr}			-	1.2	-	μC	
Reverse Recovery Current	I _{RRM}			-	14	-	A	

Notes

a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

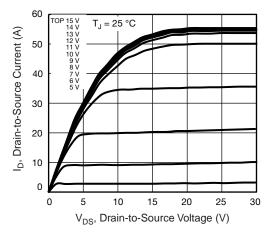


Fig. 1 - Typical Output Characteristics



Fig. 2 - Typical Output Characteristics

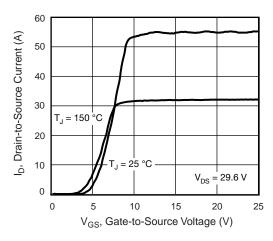


Fig. 3 - Typical Transfer Characteristics

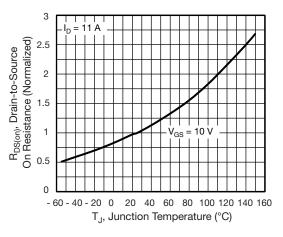


Fig. 4 - Normalized On-Resistance vs. Temperature

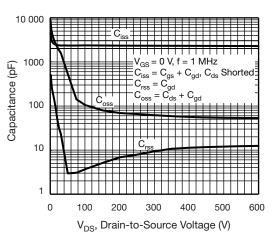


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

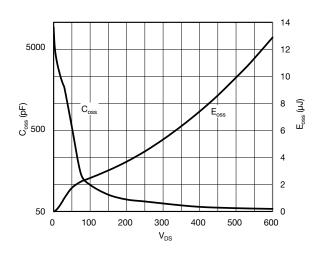


Fig. 6 - C_{oss} and E_{oss} vs. V_{DS}



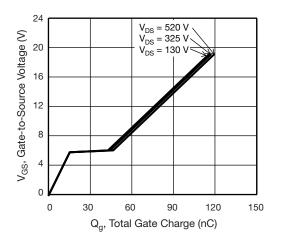


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

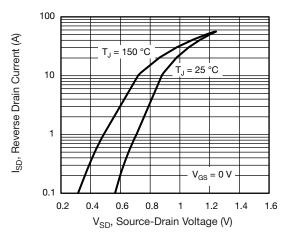


Fig. 8 - Typical Source-Drain Diode Forward Voltage

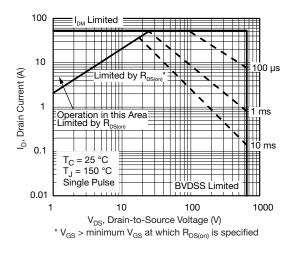


Fig. 9 - Maximum Safe Operating Area

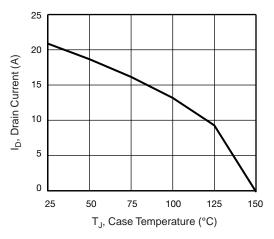


Fig. 10 - Maximum Drain Current vs. Case Temperature



Fig. 11 - Temperature vs. Drain-to-Source Voltage



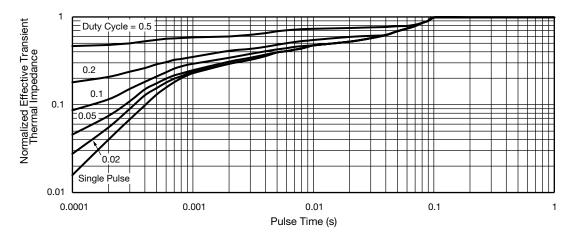


Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case



Fig. 13 - Switching Time Test Circuit



Fig. 14 - Switching Time Waveforms

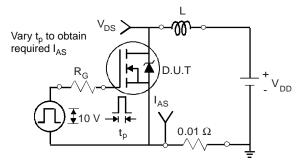


Fig. 15 - Unclamped Inductive Test Circuit

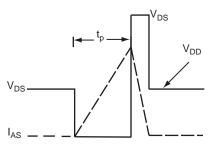


Fig. 16 - Unclamped Inductive Waveforms

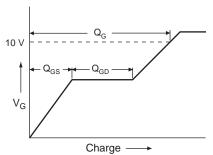
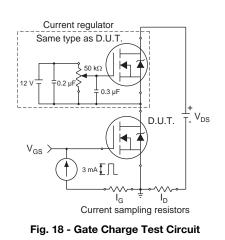
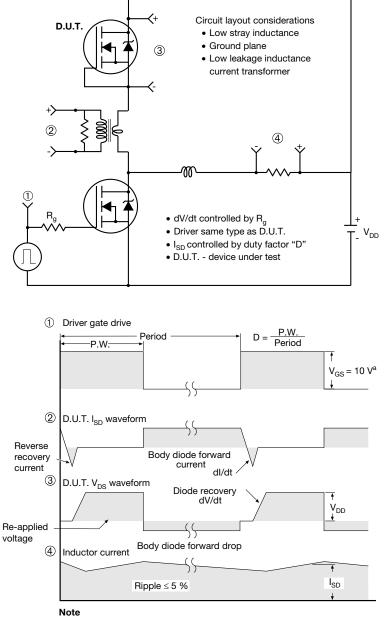


Fig. 17 - Basic Gate Charge Waveform





Peak Diode Recovery dV/dt Test Circuit



a. $V_{GS} = 5$ V for logic level devices

Fig. 19 - For N-Channel



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